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SR5000

High-Performance VXI Digital Test Subsystem



- Up to 200 MHz Data Rates
- Stimulus / Response / Real-Time Compare / Record
- 16-32 I/O Channels per Module; Expandable to 640 Inputs and 640 Outputs per System
- 64K-256K Vectors per Channel
- Algorithmic and RAM-Backed Pattern Generation
- Data Formatting with 100 ps Programmable Edge Placement
- Multi-Level Triggering and Advanced Logic Analysis
- Conditional Pattern Looping and Branching for Real-Time Test Sequence Control
- A32 / D32 Binary Transfer for High-Speed Test Program Download
- Multiple Logic Families Supported With Separate VXI Modules

50 MHz



VisTE, Visual Test Editor.

General

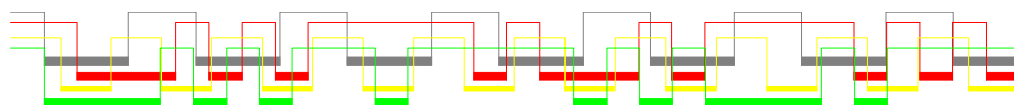
The SR5000 provides high-speed digital pattern generation, response comparison and logic analysis for serial and parallel test requirements. The SR5000 system is comprised of the SR5010A Timing / Control Module and several I/O modules that allow you to “mix and match” according to your UUT logic level requirements. These modules currently support TTL, programmable voltage, ECL, CMOS, LVDS, and PECL logic levels at data rates up to 200 MHz. Guided probe capability is also available as a separate SR5000GP module. All SR5000 modules are C-size, single-slot cards that are self-contained and require no external power or circuitry outside the VXI mainframe. The SR5000 can be configured with up to 640 inputs and 640 outputs, or 640 bidirectional channels in 16 or 32 channel increments. This provides flexibility by allowing one to select only the logic levels and the number of channels that are required for the test application.

Test Development Tools

The SR5000 comes with a suite of powerful test development tools to choose from. The SR5000 includes fully compliant VXI Plug & Play software drivers that includes a stand-alone, executable soft front panel program to interactively control the instrument. The soft panel provides complete con



SR5000GP Guided Probe Module.



trol of the instrument without requiring a particular programming environment. A standard installation program allows for quick setup and ability to get up and running in minutes. This control software also includes standardized instrument drivers to control the instrument from within the user's own application program. Both National Instruments LabView and LabWindows/CVI graphical programming languages are supported to provide interactive screens for micro-management of virtually any digital test application.

Test program development is further aided in that the SR5000 uses an ASCII message-based command set based on the SCPI-syntax (Standard Commands for Programmable Instruments) test language. The use of SCPI-syntax simplifies test program development by providing an "English-like" programming environment that is widely accepted by the test and measurement industry.

In addition, test program development is further simplified by data entry commands such as Pin Assignments. Pin Assignments allow you to group I/O pins by their logical function (address bus, data bus, etc.) and assign a field name to that pin group. Pin Assignments streamline programming by allowing you to enter patterns by referring to the UUT signal names.

To make test development even easier, an optional graphical waveform editor (WaveEdit) can be added as an add-on extension to the exist-

ing SR5000 WIN VXI Plug & Play Software Panel. WaveEdit allows you to define stimulus and response tests patterns using waveform graphics in order to represent data in the same format that you use every day. Recorded data can also be viewed in context with stimulus data, permitting you to be more productive in developing and debugging test programs.

Finally, the Visual Test Editor (VisTE) software tool provides a simple and intuitive environment for developing test programs online or offline, without the use of the SR5000 Digital Test Subsystem. Test programs are partitioned into projects. Each project represents all the parameters necessary for testing a particular device. Projects are further partitioned to represent information in the most logical format.

Fast Test Pattern Download From Slot-0

SR5000 test programs and stimulus / response test patterns may also be downloaded from the Slot-0 Controller using high-speed binary block transfers, therefore, providing the best of both worlds; ASCII based test language for simple test program development and binary block transfers for high-speed download of test programs.

To further maximize test download time, the SR5000 provides internal program storage capable of storing up to 32 different test programs. Any test program can be "activated" by selecting its test name with a simple command string.

RAM Backed and Algorithmic Pattern Generation

The SR5000 offers traditional RAM-backed pattern generation and compare, while also providing algorithmic pattern generation and compare capabilities. Test patterns that ordinarily consume large amounts of I/O memory, such as for RAM memory testing, can be reduced to just a few algorithmic commands. Algorithmic capability reduces the need for large pattern memory, increases test throughput by minimizing test download time, and reduces test programming and debug time.

SR5000 Digital Test Subsystem Modules:

- SR5010A Timing/Control
- SR5020 50 MHz TTL I/O
- SR5030 50 MHz Var. Volt. I/O
- SR5031A 50 MHz Prog. HV I/O
- SR5040 50 MHz Diff. ECL I/O
- SR5140A 100 MHz Diff. ECL I/O
- SR5240A 200 MHz Diff. ECL I/O
- SR5050 50 MHz CMOS I/O
- SR5060A 50 MHz LVDS I/O
- SR5160A 100 MHz LVDS I/O
- SR5260A 200 MHz LVDS I/O
- SR5070A 50 MHz PECL I/O
- SR5170A 100 MHz PECL I/O
- SR5270A 200 MHz PECL I/O
- SR5000GP Guided Probe



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